2013 IEEE 19th International On-Line Testing Symposium

(IOLTS 2013)

Chania, Crete, Greece
8 – 10 July 2013
Technical Papers

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**Date/Time:** Tuesday, 9 July 2013 / 10:00 – 11:20  
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K. Roy, Purdue U

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Michael Nicolaidis and Panagiota Papavramidou

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